S	Sear	ch	Note			

Application/Control N	lo.
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Applicant(s)/Patent under Reexamination

10/825,131

Examiner

Thong Q. Nguyen

NAKAGAWA ET AL.
Art Unit

2872

SEARCHED			
Class	Subclass	Date	Examiner
359	368; 383; 391-394; 819	2/14/2005	NT
250	308-310	2/14/2005	NT
250	442.11	2/14/2005	NT
74	490.09	2/14/2005	NT
		. "	
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INT	INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner		
359	391-394	2/14/2005	NT		
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SEARCH (INCLUDING SEAF	CH STRATE	GY)
	DATE	EXMR
East (search attached)	2/1 4/200	95 NT